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31 Scan-based transition test

Savir, J.; Patil, S.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on, Volume: 12, Issue: 8, Aug. 1993

Pages:1232 - 1241

[\[Abstract\]](#) [\[PDF Full-Text \(860 KB\)\]](#) **IEEE JNL**

32 BIST of PCB interconnects using boundary-scan architecture

Hassan, A.S.M.; Agarwal, V.K.; Nadeau-Dostie, B.; Rajski, J.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on, Volume: 11, Issue: 10, Oct. 1992

Pages:1278 - 1288

[\[Abstract\]](#) [\[PDF Full-Text \(1008 KB\)\]](#) **IEEE JNL**

33 Optimal diagnostic methods for wiring interconnects

Cheng, W.-T.; Lewandowski, J.L.; Wu, E.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on, Volume: 11, Issue: 9, Sept. 1992

Pages:1161 - 1166

[\[Abstract\]](#) [\[PDF Full-Text \(544 KB\)\]](#) **IEEE JNL**

34 Stuck-open testable scan-based CMOS sequential circuits

Park, B.-H.; Menon, P.R.;

Solid-State Circuits, IEEE Journal of, Volume: 27, Issue: 9, Sept. 1992

Pages:1237 - 1244

[\[Abstract\]](#) [\[PDF Full-Text \(700 KB\)\]](#) **IEEE JNL**

35 **Integration of algorithmic VLSI synthesis with testability incorporation**
Gebotys, C.H.; Elmasry, M.I.;
Solid-State Circuits, IEEE Journal of, Volume: 24, Issue: 2, April 1989
Pages:409 - 417

[\[Abstract\]](#) [\[PDF Full-Text \(712 KB\)\]](#) [IEEE JNL](#)

36 **Tree-structured LFSR synthesis scheme for pseudo-exhaustive test of VLSI circuits**

Rau, J.C.; Jone, W.B.; Chang, S.C.; Wu, Y.L.;
Computers and Digital Techniques, IEE Proceedings-, Volume: 147, Issue: 5, Sept. 2000
Pages:343 - 348

[\[Abstract\]](#) [\[PDF Full-Text \(556 KB\)\]](#) [IEE JNL](#)

37 **Low-power technique of scan-based design for test**

Lei Xu; Yihe Sun; Hongyi Chen;
Electronics Letters, Volume: 36, Issue: 23, 9 Nov. 2000
Pages:1920 - 1921

[\[Abstract\]](#) [\[PDF Full-Text \(228 KB\)\]](#) [IEE JNL](#)

38 **Efficient global strategy for designing and testing scanned sequential circuits**

Liu, B.-D.; Chen, P.-C.; Nang, J.-F.;
Computers and Digital Techniques, IEE Proceedings-, Volume: 142, Issue: 2, March 1995
Pages:170 - 176

[\[Abstract\]](#) [\[PDF Full-Text \(572 KB\)\]](#) [IEE JNL](#)

39 **An enhanced tree-structured scan chain for pseudo-exhaustive test of VLSI circuits**

Jiann-Chyi Rau; Kuo-Chun Kuo;
System-on-Chip for Real-Time Applications, 2003. Proceedings. The 3rd IEEE International Workshop on, 30 June-2 July 2003
Pages:374 - 377

[\[Abstract\]](#) [\[PDF Full-Text \(240 KB\)\]](#) [IEEE CNF](#)

40 **Improving test quality of scan-based BIST by scan chain partitioning**

Dong Xiang; Ming-Jing Chen; Jia-Guang Sun; Fujiwara, H.;
Test Symposium, 2003. ATS 2003. 12th Asian, 16-19 Nov. 2003
Pages:12 - 17

[\[Abstract\]](#) [\[PDF Full-Text \(251 KB\)\]](#) [IEEE CNF](#)

41 **Reducing scan shifts using folding scan trees**

Yotsuyanagi, H.; Kuchii, T.; Nishikawa, S.; Hashizume, M.; Kinoshita, K.;
Test Symposium, 2003. ATS 2003. 12th Asian, 16-19 Nov. 2003
Pages:6 - 11

[\[Abstract\]](#) [\[PDF Full-Text \(295 KB\)\]](#) [IEEE CNF](#)

42 Efficient diagnosis for multiple intermittent scan chain hold-time faults
Yu Huang; Huan-Yung Tseng; Wu-Tung Cheng; Alou Huang; Cheng-Ju Hsieh; Ting Hung;

Test Symposium, 2003. ATS 2003. 12th Asian , 16-19 Nov. 2003
Pages:44 - 49

[\[Abstract\]](#) [\[PDF Full-Text \(245 KB\)\]](#) [IEEE CNF](#)

43 Test data manipulation techniques for energy-frugal, rapid scan testing
Sinanoglu, O.; Orailoglu, A.;

Test Symposium, 2003. ATS 2003. 12th Asian , 16-19 Nov. 2003
Pages:202 - 207

[\[Abstract\]](#) [\[PDF Full-Text \(279 KB\)\]](#) [IEEE CNF](#)

44 Optimizing test access mechanism under constraints by genetic local search algorithm

Yingxiang Wang; Weikang Huang;

Test Symposium, 2003. ATS 2003. 12th Asian , 16-19 Nov. 2003
Pages:428 - 431

[\[Abstract\]](#) [\[PDF Full-Text \(232 KB\)\]](#) [IEEE CNF](#)

45 Designing multiple scan chains for systems-on-chip

Quasem, M.S.; Gupta, S.;

Test Symposium, 2003. ATS 2003. 12th Asian , 16-19 Nov. 2003
Pages:424 - 427

[\[Abstract\]](#) [\[PDF Full-Text \(290 KB\)\]](#) [IEEE CNF](#)

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